	Application No.	Applicant(s)	Con
Notice of Allowability	10/621,218_	JOHNSON ET ÅL.	
	Examiner	Art Unit	<del></del>
	Craig A. Thompson	2813	
The MAILING DATE of this communication All claims being allowable, PROSECUTION ON THE MER herewith (or previously mailed), a Notice of Allowance (PT NOTICE OF ALLOWABILITY IS NOT A GRANT OF PAT of the Office or upon petition by the applicant. See 37 CFI	on appears on the cover sheet we RITS IS (OR REMAINS) CLOSED i OL-85) or other appropriate comm ENT RIGHTS. This application is R 1.313 and MPEP 1308.	ith the correspondence address this application. If not included	j
1. This communication is responsive to communication	n of //16/2003.		
2. The allowed claim(s) is/are 8 and 9.		· · · · · · · · · · · · · · · · · · ·	
3. X The drawings filed on 16 July 2003 are accepted by	the Examiner.		
4. ☐ Acknowledgment is made of a claim for foreign pri a) ☐ All b) ☐ Some* c) ☐ None of the:  1. ☐ Certified copies of the priority declarate.		or (f).	·.
Certified copies of the priority documen     Certified copies of the priority document			
<ol> <li>Certified copies of the priority document</li> <li>Copies of the certified copies of the priority</li> </ol>	is have been received in Application	on No	
International Bureau (PCT Rule 17.2(a)	ntry documents have been received	o in this national stage application	on from the
* Certified copies not received:	<i>,</i>		
Applicant has THREE MONTHS FROM THE "MAILING I noted below. Failure to timely comply will result in ABAN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.  5. A SUBSTITUTE OATH OR DECLARATION must be INFORMAL PATENT APPLICATION (DTO 452) in the INFORMAL	DONMENT of this application.	1 to 1	
IN STRING AFFERDATION (FIG-152) WILL	cn gives reason(s) why the oath or	AMINER'S AMENDMENT of NO declaration is deficient.	TICE OF
6. CORRECTED DRAWINGS (as "replacement sheets	") must be submitted.		
(a) ☐ including changes required by the Notice of Dra	ftsperson's Patent Drawing Review	v ( PTO-948) attached	
1) hereto or 2) to Paper No./Mail Date			
<ul><li>(b) ☐ including changes required by the attached Example Paper No./Mail Date</li></ul>			•
Identifying indicia such as the application number (see 37 each sheet. Replacement sheet(s) should be labeled as su	CFR 1.84(c)) should be written on th ch in the header according to 37 CFI	e drawings in the front (not the ba R 1.121(d).	ick) of
7. DEPOSIT OF and/or INFORMATION about the attached Examiner's comment regarding REQUIREN	deposit of BIOLOGICAL MATE ENT FOR THE DEPOSIT OF BIO	ERIAL must be submitted. Not DLOGICAL MATERIAL.	e the
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Attachment(s)	*		
1. ☑ Notice of References Cited (PTO-892)	5 ☐ Notice of Info	ormal Patent Application (PTO-1	<b>5</b> 2\
2.  Notice of Draftperson's Patent Drawing Review (PTO-	948) 6. 🗌 Interview Su	mmary (PTO-413),	52)
3. ☑ Information Disclosure Statements (PTO-1449 or PTC Paper No./Mail Date 7/16/03	0/SB/08), 7. ☐ Examiner's A	Mail Date Amendment/Comment	
4. Examiner's Comment Regarding Requirement for Dep	osit 8. 🛭 Examiner's 8	Statement of Reasons for Allowa	nce
of Biological Material	9. 🗌 Öther		
		Craig A. Thompson Primary Examiner Art Unit: 2813	
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## **DETAILED ACTION**

The examiner confirmed on 28 May 2004 in a telephone interview with Mr. Michael Stallman that the preliminary amendment filed with this application cancelled claims 1-7 and that claims 8 and 9 are pending.

## Allowable Subject Matter

Claims 8 and 9 are allowed.

## **REASONS FOR ALLOWANCE**

The following is an examiner's statement of reasons for allowance: prior art of record does not describe or suggest applicants' invention set forth in claim 8, a test structure for optical monitoring of erosion on a wafer comprising an upper layer with an array formed by an alternating pattern of metal and dielectric material and a lowe layer defined by a flat reflective material to reduce the number of measurement variables associated with the optical monitoring of the test structure. Similarly, prior art of record does not describe or suggest the invention of claim 9, a method for monitoring erosion comprising steps of: (a) forming a test structure in the scribe lines between dies of the wafer with the test structure including at least an upper layer having an array formed by an alternating pattern of metal and dielectric material and a lower layer defined by a flat reflecting material, (b) directing a probe beam of radiation to reflect off the test structure, and (c) monitoring the probe beam, in the context of the recited process.

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Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

## Cited Prior Art

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Ravid et al. (U.S. Patent No. 6,654,108, filed 20 February 2001) teaches a test structure for metal CMP process control (abstract and title). The structure includes at least two structures aligned along a vertical axis (abstract and figure 3)

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Conclusion

Any inquiry concerning this communication or earlier communications from the

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examiner should be directed to Craig A. Thompson whose telephone number is

(571)272-1699. The examiner can normally be reached on Monday-Friday 8:00 am -

4:30 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Carl Whitehead, Jr. can be reached on (571)272-1702. The fax phone

number for the organization where this application or proceeding is assigned is 703-

872-9306.

Information regarding the status of an application may be obtained from the

Patent Application Information Retrieval (PAIR) system. Status information for

published applications may be obtained from either Private PAIR or Public PAIR.

Status information for unpublished applications is available through Private PAIR only.

For more information about the PAIR system, see http://pair-direct.uspto.gov. Should

you have questions on access to the Private PAIR system, contact the Electronic

Business Center (EBC) at 866-217-9197 (toll-free).

Craig A. Thompson Primary Examiner

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28 May 2004